Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/650,574	KIM ET AL.	
Examiner	Art Unit	

2874

James D. Stein

SEARCHED					
Class	Subclass	Date	Examiner		
385	52,88,90, 97	6/21/2005	JDS		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
files	removed	6/21/2005	JDS		
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SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
See attached EAST search history	6/21/2005	JDS
INSPEC and IEEE databases: waveguide, planar, fiber, substrate, alignement, table, surface, rotation	6/21/2005	JDS
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